

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2440	SERIAL NO. 10/719,640
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) <div style="position: absolute; top: 10px; left: 10px; border: 1px solid black; border-radius: 50%; padding: 5px; text-align: center;"> SEP 27 2004 U.S. PATENT & TRADEMARK OFFICE </div>				APPLICANT: Terry L. Gilton et al.	
				FILING DATE November 21, 2003	GROUP 2813

U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA						
	AB						
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	AD						
	AE						
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	AI						

FOREIGN PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AJ						
	AK						
	AL						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
TSP	AM		Lee, Hyun-Yong et al., "Lithographic Properties of SiN _x and Se ₇₅ Ge ₂₅ Thin Films as the Low-Energy Ion-Beam Resist", Proceedings of the 5 th International Conference on Properties and Applications of Dielectric Materials, 25-30 May 1997, p.635-638
	AN		
	AO		

EXAMINER	DATE CONSIDERED 10/22/04
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.